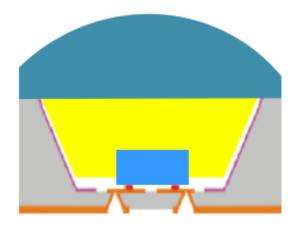
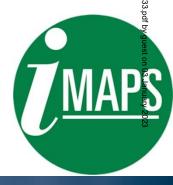
Lithography for Wafer Level Packaging for LED Manufacturing

Tim McCrone Applications Engineer

SUSS MicroTec March 2013



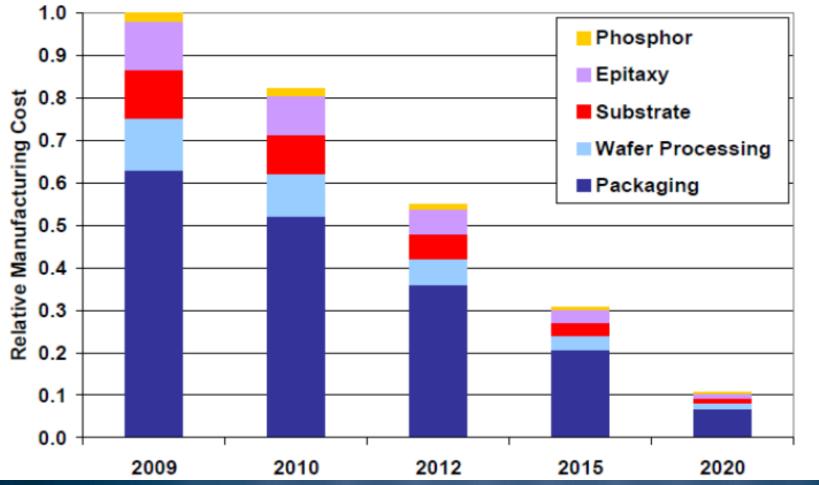


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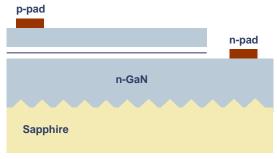
INTRODUCTION

LED designs trends toward higher efficiency and brightness at a lower cost.

The primary cost of LED electronics is found in the packaging of the material.



INTRODUCTION

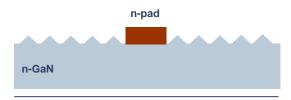


Conventional LED device with patterend sapphire substrate (PSS) (essentially all LED chip makers)





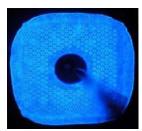
- + Relatively inexpensive
- Up to 30% active surface lost to the Mesa
- Transparent or small contact needed on the p-side
- Current crowding due to poor conductivity of n-GaN increase total resistance



Conductor / Metall

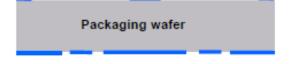
Thin-film vertical LED device with n-GaN texturing with substrate removal (Osram, Lumileds, Semileds, Cree, Luminus)

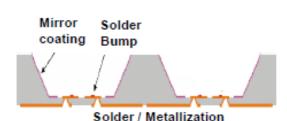


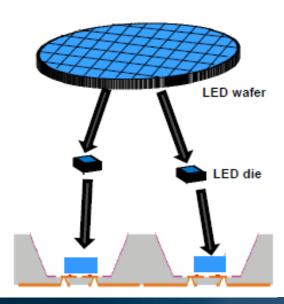


- Complexity and Cost
- + Good thermal properties
- + Larger active area (no MESA)
- + n-GaN can be thinned down to bring active layer close to the surface and improve light extraction (surface emitter)
- + Lower resistance

INTRODUCTION





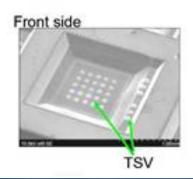


Advantages of wafer level packaging:

Small form factors
Excellent scalability to larger wafer sizes

Challenges with wafer level packaging:

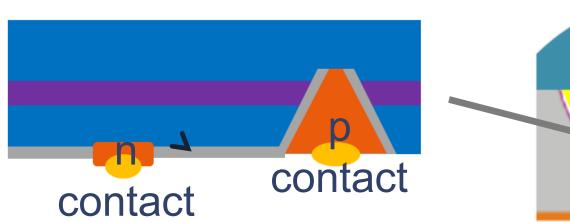
Conformal coating
Exposure in deep vias and grooves
TSV creation and isolation

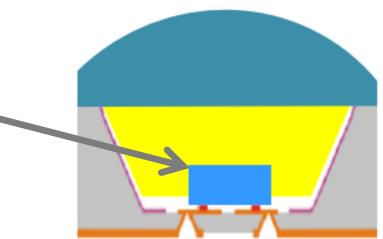




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Using vias in LED device structure and packaging introduces the challenge of being able to coat and pattern in high aspect ratio structures





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SPRAY COATING: COMPARISONS

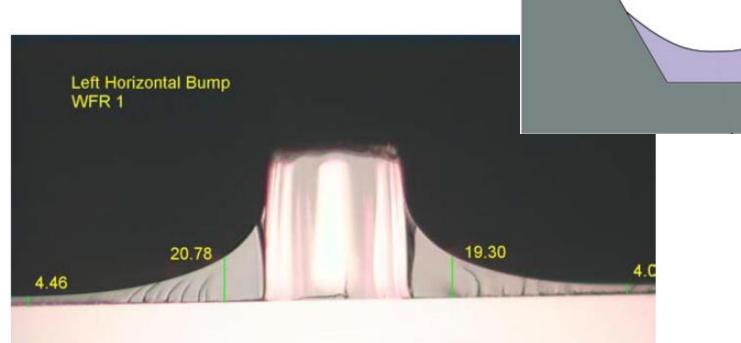
Spin Coating over Topography:

Easy to set up for small topography steps

Higher throughput

High aspect ratio structures cannot be coated

due to gravity and surface tension



SPRAY COATING: COMPARISONS

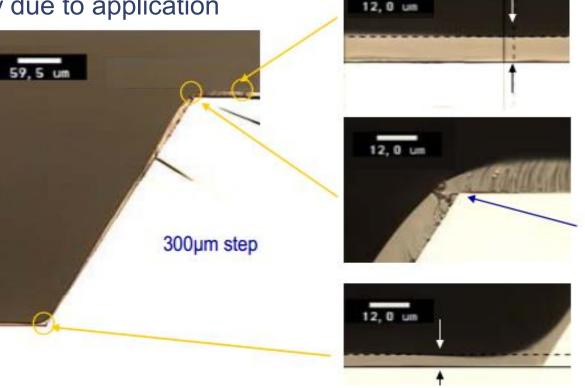
Spray Coating over Topography:

Reliable coverage at corners, in trenches and grooves

Higher material utilization fraction than spin coating

Great film uniformity due to application

method



7µm top

5μm on top of the edge

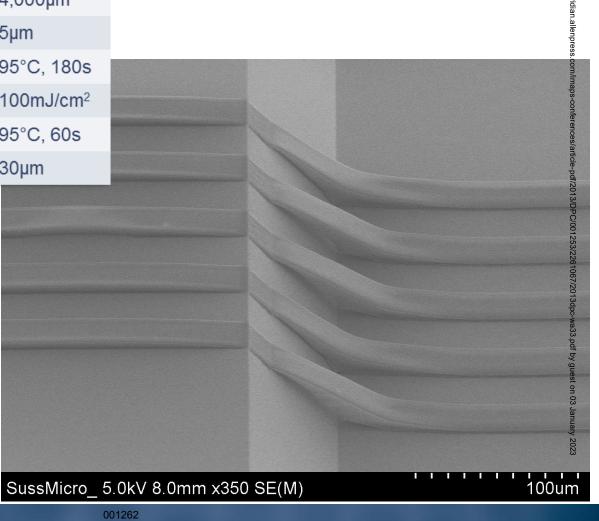
SPRAY COATING: AZ4999 DNQ/NOVOLAK



SUSS MicroTec

SPRAY COATING NEGATIVE RESISTS: SU8-3050

SU8-3050 (diluted)	
Cavity depth (KOH etched):	100µm
Cavity width / length:	4,000µm
Film Thickness (top / bottom):	5µm
Softbake:	95°C, 180s
Exposure Dose:	100mJ/cm ²
Post Exposure Bake (PEB):	95°C, 60s
CD of L/S Resolution Pattern:	30µm



MicroTec

100um

SPRAY COATING NEGATIVE RESISTS: SU8-3050

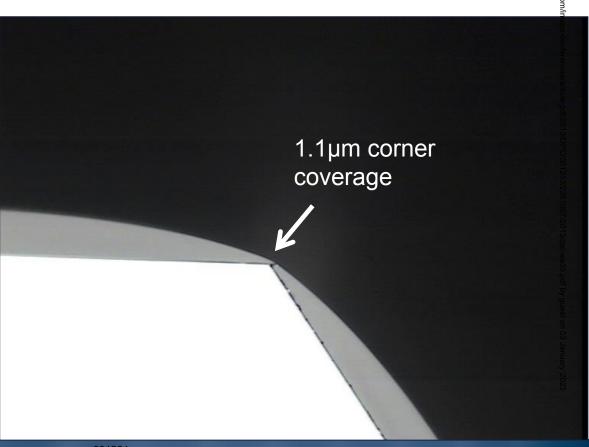
	MAN OF WAY STANDED
SU8-3050 (diluted)	
Cavity depth (KOH etched):	100µm
Cavity width / length:	4,000µm
Film Thickness (top / bottom):	5µm
Exposure Dose:	100mJ/cm ²
Softbake (after exposure):	95°C, 180s
Post Exposure Bake (PEB)	95°C, 60s
CD of L/S Resolution Pattern:	30µm

SussMicro_ 5.0kV 8.0mm x350 SE(M)

SUSS MicroTec

SPRAY COATING NEGATIVE RESISTS: SU8-3050

SU8-3050 (diluted)	
Cavity depth (KOH etched):	100µm
Trench width:	800µm
Film Thickness (top / bottom):	5µm
Exposure Dose:	250mJ/cm ²
Softbake (after exposure):	95°C, 180s
Post Exposure Bake (PEB)	95°C, 60s
CD of L/S Resolution Pattern:	Flood Exp.



EXAMPLE WHY NEGATIVE SPRAY RESIST IS IMPORTANT

MicroTec

Goal:

Negative slope Topography:

Resist structures: Only in the bottom of cavity



After Develop

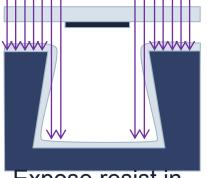
Resist Residues

Positive acting resist

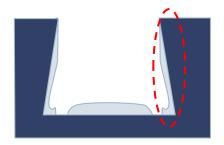
Negative acting resist



Spray coating



Expose resist in bottom of structure



Develop



Spray Coating



Expose resist in bottom of structure



Develop

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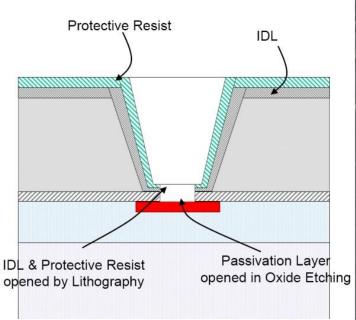
SPRAY COATING: SPIN-ON DIELECTRICS

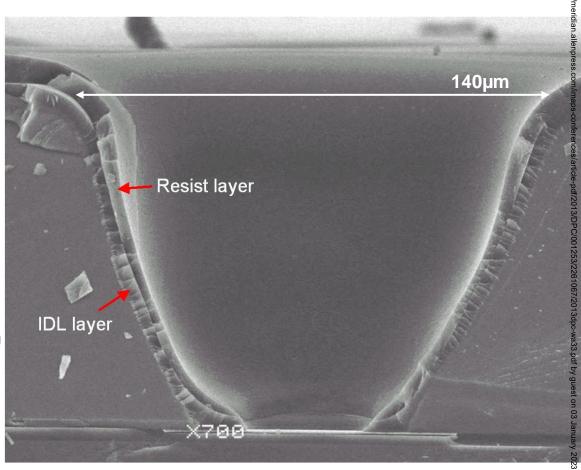
Material	Supplier	Polymer Type	Developer
HD 4100	HD Microsystems	Polyimide	Org. Developer
Durimide 7005	Fujifilm	Polyimide	Org. Developer
Cyclotene 4024-40	Dow Chemical	BCB	Org. Developer
Intervia 8023	Rohm & Haas	Epoxy / Novolak	TMAH (aq)

Material	Supplier	Polymer Type	Developer
WPR-5200	JSR Micro	Phenolic Resin	TMAH (aq)
HD8820	HD Microsystems	PBO	TMAH (aq)
CRC-8600	Sumitomo Bakelite	РВО	TMAH (aq)
PW-1200	Toray Industries	Polyimide	TMAH (aq)
Cyclotene P6505	Dow Chemical	ВСВ	TMAH (aq)

Generally, positive-acting passivation materials are more suitable for spray coating.

SPRAY COATING: COATING IN VIAS





Source: Schott OPTO WLP

Proximity printing is a well established and cost efficient process in LED device manufacturing with more than 70% share

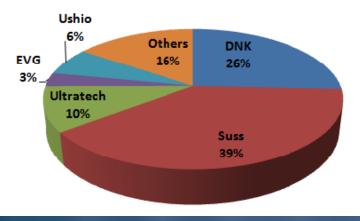
WLP generally has low pin counts with larger pads.

Aligners are optimized for resolution at specific proximities or contact

To achieve the highest resolution over a range of gaps in a device the light source must be shaped to achieve the best results

Relative Share of Installed LED Systems





Relative share of installed LED systems (over a total estimate of ~ 465 tools)

MO EXPOSURE OPTICS



Diffraction Reduction

+Defines illumination settings by Illumination Filter Plate (IFP)

"Angle defining element"



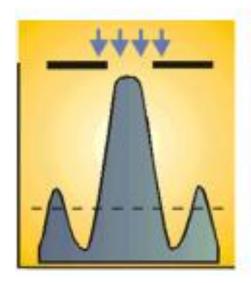
MO Integrator (1)

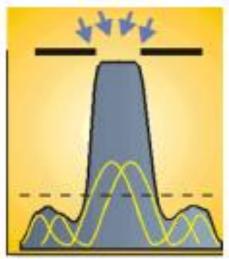
+Decouples illumination from lamp position



MO Integrator (2)

+Ensures uniform illumination of mask field





Parallel illumination causes high intensity second order effects

Using illumination from multiple angles at general intensities reduces diffraction effects

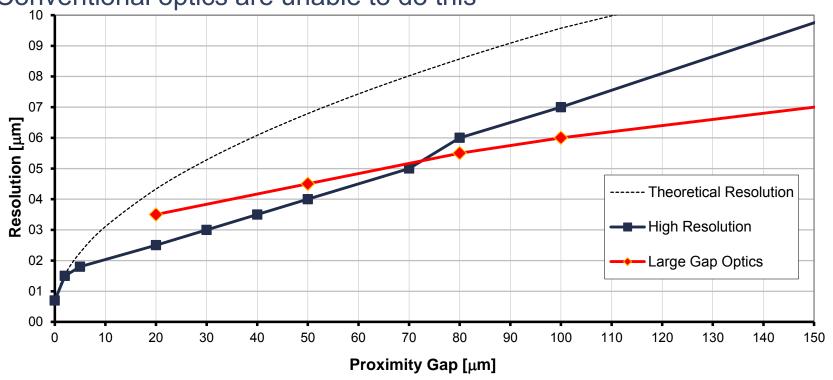
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MO EXPOSURE OPTICS

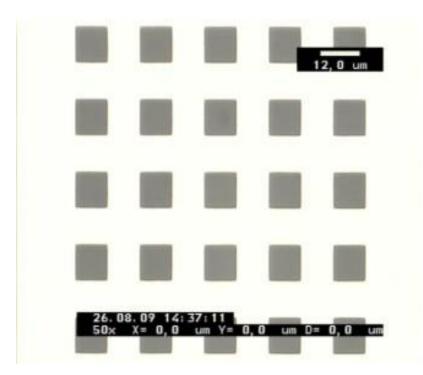
High stability of resolution over a larger depth of field allows for large exposure gaps, leading to fewer mask contamination defects

Diffraction limiting effects limits resolution loss over the depth of a device

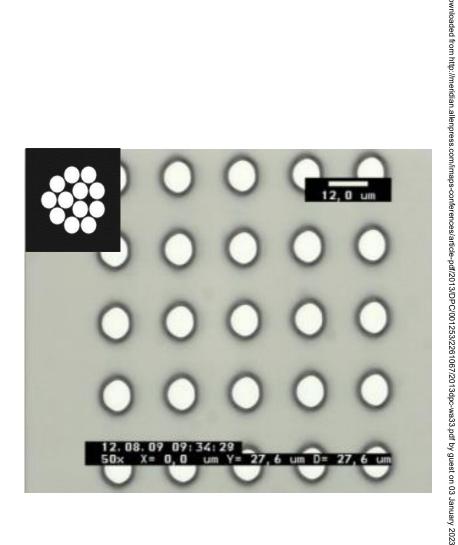
Conventional optics are unable to do this



CHANGING SOURCE SHAPE TO OPTIMIZE A PROCESS

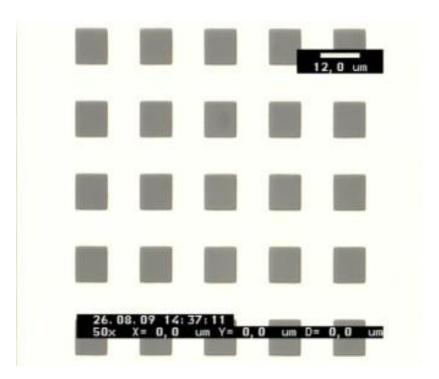


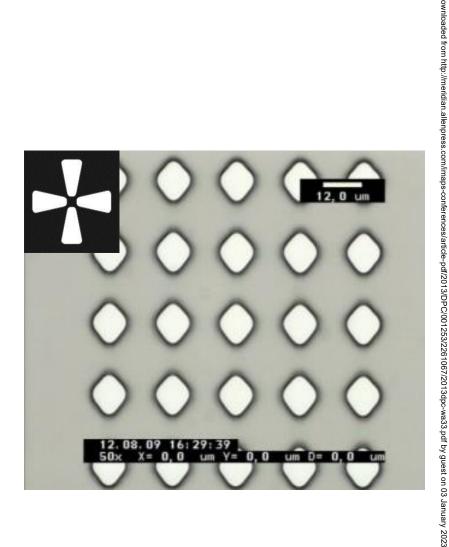
1.2µm thick resist (AZ 4110), 100µm Proximity Gap, SUSS MA8



CHANGING SOURCE SHAPE TO OPTIMIZE A PROCESS

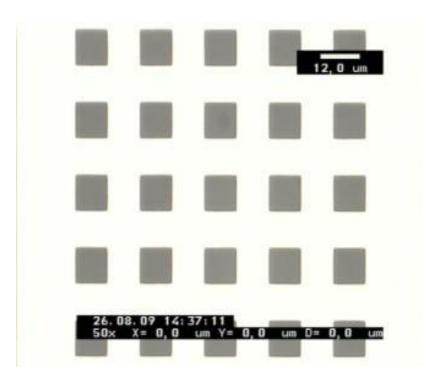


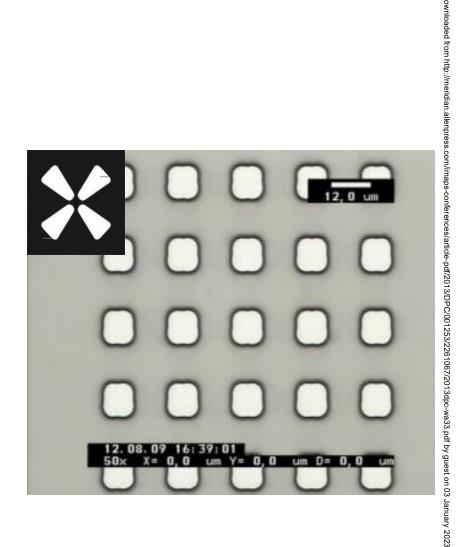




CHANGING SOURCE SHAPE TO OPTIMIZE A PROCESS



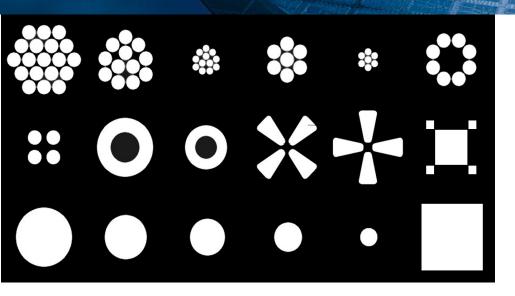




CUSTOMIZED ILLUMINATION:

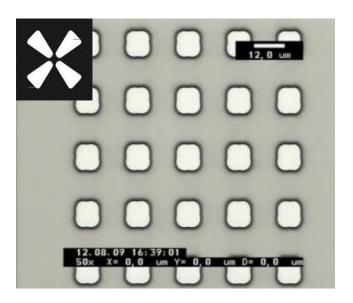
CHANGING SOURCE SHAPE TO OPTIMIZE A PROCESS

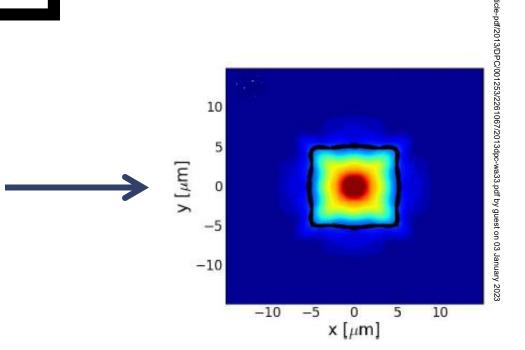




Large selection of illumination filter plates to optimize specific structures

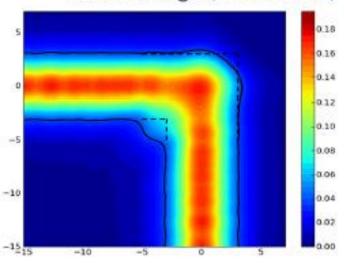
GenISys is a powerful tool to help optimize the illumination source for a process

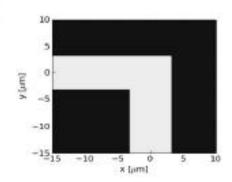




GENISYS SOFTWARE

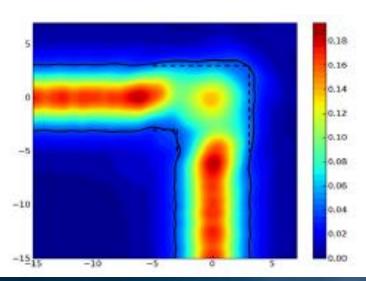


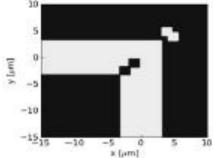




Mask pattern

GenlSys also assists with corrective features in mask design





OPC assist features

Spray coating of both negative and positive acting dielectrics and photoresists allows for the patterning of 3D structures on a wafer and the isolation of TSVs.

Aligners can be used for patterning of packaging wafers and for creation of LEDs.

GenISys software quickly optimizes processes without use of lab time or trial masks